



Docket No.: H6808.0032/P032
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Shuichi Takeuchi et al.

Application No.: 10/750,838

Confirmation No.: 2502

Filed: January 5, 2004

Art Unit: N/A

For: SCANNING ELECTRON MICROSCOPE
AND SAMPLE OBSERVING METHOD
USING IT

Examiner: Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT (IDS)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 CFR 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO/SB/08. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is filed before the mailing date of a first Office Action on the merits as far as is known to the undersigned (37 CFR 1.97(b)(3)).

A summary/abstract translation of the non-English language references is enclosed.

In accordance with 37 CFR 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other material information as defined in 37 CFR 1.56(a) exists. In accordance with 37 CFR

1.97(h), the filing of this Information Disclosure statement shall not be construed to be an admission that any patent, publication or other information referred to therein is "prior art" for this invention unless specifically designated as such.

It is submitted that the Information Disclosure Statement is in compliance with 37 CFR 1.98 and the Examiner is respectfully requested to consider the listed references.

The Director is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 04-1073, under Order No. H6808.0032/P032. A duplicate copy of this paper is enclosed.

Dated: June 8, 2004

Respectfully submitted,

By 

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PTO/SB/08a/b (08-03)
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U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/750,838-Conf. #2502
				Filing Date	January 5, 2004
				First Named Inventor	Shuichi Takeuchi
				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	H6808.0032/P032

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA**	6,538,249	03-25-2003	Takane et al.	
	AB**	6,353,222	03-05-2002	Noam Dotan	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
	BA	JP 2001-84944	03-30-2001			
	BB	JP 2001-118537	04-27-2001			
	BC	JP 2001-344599	12-14-2001			
	BD	JP 2002-75263	03-15-2002			
	BE	JP 2002-184336	06-28-2002			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. **CITE NO.: Those patent(s) or publication(s) which are marked with an double asterisk (**) next to the Cite No. are not supplied because they were previously cited by or submitted to the Office in a prior application relied upon in this application for an earlier filing date under 35 U.S.C. 120. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	CA	A. Muto et al., "Attempts to Improve SEM Image Quality by Special Imaging Feature." Proceedings of the Fifty-Eighth Annual Meeting of the Japanese Society of Electron Microscopy, May 14-16, 2002, pp.246. English Translation.	
	CB	M. Sato et al., "Depth of Field at High Magnifications of Scanning Electron Microscopes." J. Vac. Sci. Technol. B 18(6), Nov/Dec. 2000, pp.3047-3051.	
	CC	T. Kogashiwa et al., "Automatic Adjustment Function of Optical Axis, and automatic Expansion Function of Focal Depth." SCAN TECH 2002, Preliminary Report, September 2002, pp. 2-6. English Translation.	
	CD	Norio Baba, "Three-dimensional Automatic Measurement by the Stereoscopic Observation Method." SCAN TECH 2000, Preliminary Report, September 2000, pp. 28-32. English Translation.	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.